MSKSEMI 美森科













ESD

T∖

TSS

MOV

GDT

PIFD

IRF7416TRPBF(MS)

Product specification





Features

- -30V,-10A, RDS(ON) =15mΩ@VGS = -10V
- Fast switching
- Green Device Available
- Suit for -4.5V Gate Drive Applications

Application

- MB / VGA / Vcore
- POL Applications
- Load Switch
- LED Application

BVDSS	RDSON	ID
-30V	15mΩ	-10A

Reference News

PACKAGE OUTLINE	Pin Configuration	Marking		
SOP-8	G	MSKSEMI IRF7416 MS *** Note: ****Representative production cycle		

Absolute Maximum Ratings Tc=25℃ unless otherwise noted

Symbol	Parameter	Rating	Units
Vos	Drain-Source Voltage	-30	V
Vgs	Gate-Source Voltage	±20	V
L	Drain Current - Continuous (T _C =25°C)	-10	А
lD	Drain Current - Continuous (T _C =100°C)	-5.1	A
І _{рм}	Drain Current - Pulsed1	-40	А
Po	Power Dissipation (T _C =25°C)	2.1	W
Fυ	Power Dissipation - Derate above 25°C	0.017	W/°C
T _{STG}	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C

Thermal Characteristics

Symbol	Parameter	Тур.	Max.	Unit
R _{0JA}	Thermal Resistance Junction to ambient		60	°C/W



Electrical Characteristics (T_J=25 °C, unless otherwise noted)

Off Characteristics

Symbol	Parameter Conditions		Min.	Тур.	Max.	Unit
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D = - 250uA	-30			٧
△BV _{DSS} /△T _J	BV _{DSS} Temperature Coefficient	Reference to 25°C , I _D =-1mA		-0.03		V/°C
	Drain-Source Leakage Current	V _{DS} =-30V , V _{GS} =0V , T _J =25°C			-1	uA
I _{DSS}		V _{DS} =-24V , V _{GS} =0V , T _J =125°C			-10	uA
I _{GSS}	Gate-Source Leakage Current	V _{GS} = ±20V , V _{DS} =0V			±100	nA

On Characteristics

R _{DS(ON)} Static Drain-Source On-Resistance	V _{GS} =-10V , I _D =-8A		15.0	20	mΩ	
TUDS(UN) Static Drain-Source Off-Resistance		V _{GS} =-4.5V , I _D =-5A		25.6	32	mΩ
$V_{\text{GS(th)}}$	Gate Threshold Voltage)/ -)/	-1.0	-1.6	-2.5	V
${}^{\vartriangle}V_{GS(th)}$	V _{GS(th)} Temperature Coefficient	V _{GS} =V _{DS} , I _D =-250uA		4		mV/°C
gfs	Forward Transconductance	V _{DS} =-10V , I _D =-3A		6.8	-	S

Dynamic and switching Characteristics

_ 1	11		
	1 1		
_ 3	.4		nC
_ 4	.2		
_ 5	8.8		
_ 18	8.8		no
_ 46	6.9		ns
_ 12	2.3		
_ 12	250		
_ 10	60		pF
_ 9	90		
-	4 	4.2 5.8 18.8 46.9 12.3 1250 160	4.2 5.8 18.8 46.9 12.3 1250 160 90

Drain-Source Diode Characteristics and Maximum Ratings

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
ls	Continuous Source Current	V _G =V _D =0V,Force Current			-10	Α
lsм	Pulsed Source Current	VG-VD-0V , I orde durient			-20	Α
VsD	Diode Forward Voltage	V _{GS} =0V , I _S =-1A , T _J =25°C			-1.3	V

Note:

- Repetitive Rating : Pulsed width limited by maximum junction temperature. The data tested by pulsed , pulse width ≤ 300 us , duty cycle $\leq 2\%$. 1.
- 2.
- 3. Essentially independent of operating temperature.

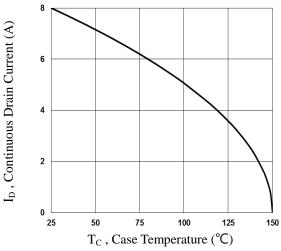


Fig.1 Continuous Drain Current vs. T_c

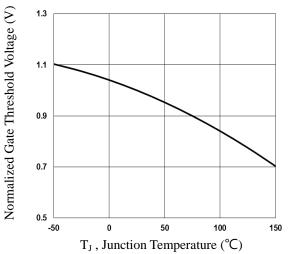


Fig.3 Normalized V_{th} vs. T_J

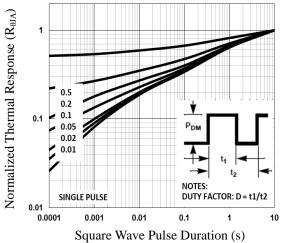


Fig.5 Normalized Transient Impedance

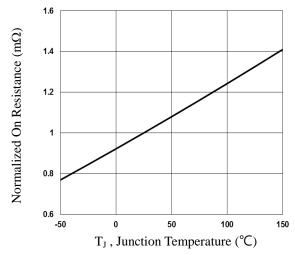


Fig.2 Normalized RDSON vs. T_J

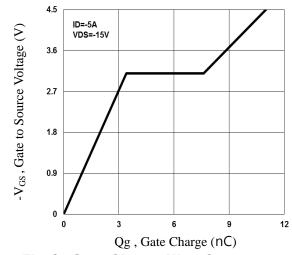


Fig.4 Gate Charge Waveform

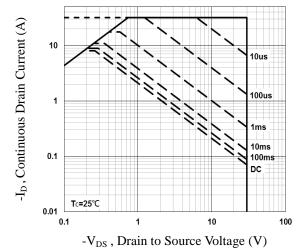
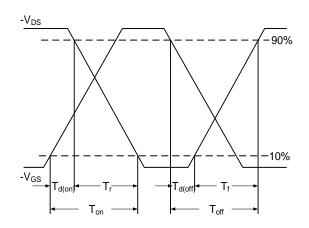


Fig.6 Maximum Safe Operation Area





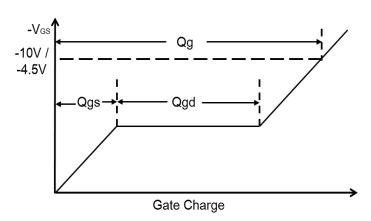
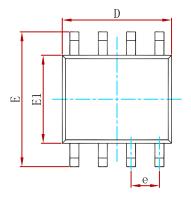
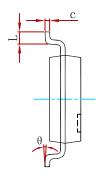


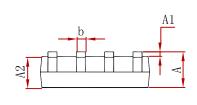
Fig.8 Gate Charge Waveform



PACKAGE MECHANICAL DATA

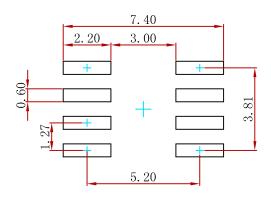






Symbol	Dimensions In Millimeters		Dimensions In Inches	
Symbol	Min	Max	Min	Max
A	1.350	1.750	0.053	0.069
A1	0.100	0. 250	0.004	0.010
A2	1.350	1.550	0.053	0.061
b	0.330	0. 510	0.013	0.020
С	0.170	0. 250	0.007	0.010
D	4.800	5. 000	0. 189	0. 197
e	1. 270	(BSC)	0.050	(BSC)
Е	5.800	6. 200	0. 228	0. 244
E1	3.800	4. 000	0. 150	0. 157
L	0.400	1. 270	0.016	0.050
θ	0°	8°	0°	8°

Suggested Pad Layout



- 1.Controlling dimension:in millimeters.
- 2.General tolerance:± 0.05mm.
 3.The pad layout is for reference purposes only.

REEL SPECIFICATION

P/N	PKG	QTY
IRF7416TRPBF(MS)	SOP-8	3000



Attention

- Any and all MSKSEMI Semiconductor products described or contained herein do not have specifications that can handle applications that require extremely high levels of reliability, such as life-support systems, aircraft's control systems, or other applications whose failure can be reasonably expected to result in serious physical and/or material damage. Consult with your MSKSEMI Semiconductor representative nearest you before using any MSKSEMI Semiconductor products described or contained herein in such applications.
- MSKSEMI Semiconductor assumes no responsibility for equipment failures that result from using products at values that exceed, even momentarily, rated values (such as maximum ratings, operating condition ranges, or other parameters) listed in products specifications of any and all MSKSEMI Semiconductor products described or contained herein.
- Specifications of any and all MSKSEMI Semiconductor products described or contained herein stipulate the performance, characteristics, and functions of the described products in the independent state, and are not guarantees of the performance, characteristics, and functions of the described products as mounted in the customer's products or equipment. To verify symptoms and states that cannot be evaluated in an independent device, the customer should always evaluate and test devices mounted in the customer'sproducts or equipment.
- MSKSEMI Semiconductor. strives to supply high-quality high-reliability products. However, any and all semiconductor products fail with someprobability. It is possiblethat these probabilistic failures could give rise to accidents or events that could endanger human lives, that could give rise to smoke or fire, or that could cause damage to other property. When designing equipment, adopt safety measures so that these kinds of accidents or events cannot occur. Such measures include but are not limited to protective circuits anderror prevention circuitsfor safedesign, redundant design, and structural design.
- In the event that any or all MSKSEMI Semiconductor products (including technical data, services) described or contained herein are controlled under any of applicable local export control laws and regulations, such products must not be exported without obtaining the export license from theauthorities concerned in accordance with the above law.
- No part of this publication may be reproduced or transmitted in any form or by any means, electronic or mechanical, including photocopying and recording, or any information storage or retrieval system, or otherwise, without the prior written permission of MSKSEMI Semiconductor.
- Information (including circuit diagrams and circuit parameters) herein is for example only; it is not guaranteed for volume production. MSKSEMI Semiconductor believes information herein is accurate and reliable, but no guarantees are made or implied regarding its use or any infringements of intellectual property rights or other rights of third parties.
- Any and all information described or contained herein are subject to change without notice due to product/technology improvement, etc. Whendesigning equipment, referto the "Delivery Specification" for the MSKSEMI Semiconductor productthat you intend to use.